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## PAPER

## **Electronic Supplementary Information (ESI)**

## Electron beam induced tunneling magnetoresistance in spatially confined manganite bridges

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**Figure S-1.** SEM imaging dramatically changes the resistance of LPCMO microbridges. (a) The SEM image (SE mode; SEM mag x6.8k) of a 5  $\mu$ m by 5  $\mu$ m LPCMO bridge; the dark spot is where the higher magnification (SEM mag x10k) SEM image is taken. (b) The temperature dependences of the normalized resistance of the 5  $\mu$ m by 5  $\mu$ m microbridge before and after the SEM imaging is carried out.



**Figure S-2.** I-V characteristics at (a) 50 K, (b) 100 K, and (c) 108 K. In the narrow LPCMO film, there exists small numbers of ferromagnetic domains which possess different initial sizes/shapes/magnetization directions in a certain temperature range. In this situation, the spin-torque effect could be involved when conduction electrons are traveling among the ferromagnetic domains.<sup>35</sup> At (c) 108 K, we observe hysteric and symmetric I-V characteristics which might be due to the spin-torque effect when the conduction electrons are traveling through a larger number of ferromagnetic domains along the current path(s). On the other hand, hysteresis and asymmetric I-V characteristics were observed at (b) 100 K, possibly due to the spin-torque effect in a smaller number of domains. This seems reasonable since the ferromagnetic domains grow and percolate with each other as the temperature decreases.<sup>22-25</sup> At low temperature ((a) and (b); T  $\leq$  100 K), the current induced Joule heating is also important, marked in red arrows (a) and (b).<sup>R1</sup>



**Figure S-3.** The evolution of the temperature dependence of the (a) negative  $MR_{MAX}$  and the (b) positive  $MR_{MAX}$  as the number of e-beam scans varies. Notice that the negative MR is very similar before and after e-beam scanning while there is a clear difference for the positive MR. The increase in the positive MR with e-beam scanning is attributed to the creation of the TMR effect in the sample. (c) The number of e-beam scans modifies the temperature at which the TMR<sub>max</sub> occurs. As the e-beam dose increases the TMR<sub>MAX</sub> tends to occur at slightly lower temperature (indicated with the red arrow).



**Figure S-4.** The temperature dependence of the (a) negative  $MR_{MAX}$  and the (b) positive  $MR_{MAX}$  of the narrow channel microbridge (2 by 20  $\mu$ m). The positive MR values near 107 K show a dramatic increase when the e-beam is scanned across the sample whereas the negative MR values do not show noticeable changes at any temperature.

References

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<sup>[</sup>R1] J.-C. Wu, H. Sun, H.-X. Da, and Z.-Y. Li, Appl. Phys. Lett. 2007, 81, 103501.